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## ABSTRACT

This work reports a quasi-two-dimensional electron gas (q-2DEG) system at the interface of two wideband-gap insulators, (TiO<sub>2</sub>-terminated) SrTiO<sub>3</sub> and LaScO<sub>3</sub>, with a minimum thickness of 4-unit cell (uc). The highly crystalline and abrupt heterointerface is confirmed with high-resolution electron microscopy. The mixed Ti<sup>4+</sup> and Ti<sup>3+</sup> valence states (for 4 uc of LaScO<sub>3</sub>) obtained from the x-ray photoelectron spectroscopy study suggest an intrinsic electronic reconstruction at the interface, leading to a metallic nature. This origin is well supported by density functional theory calculations that reveal an emergence of 3.3 states/eV/spin at the Fermi level for 4 uc in accordance with the polar catastrophe model. The study offers one more perovskite heterostructure, like LaAlO<sub>3</sub>/SrTiO<sub>3</sub>, for unraveling the q-2DEG phenomena toward a clear mechanism and futuristic applications.

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The lattice symmetry breaking at the heterointerface of layered perovskite oxides leads to unique phenomena,<sup>1–7</sup> absent in individual layers. The most acknowledged example is the quasi two-dimensional electron gas (q-2DEG) with a very high carrier mobility at the interface of two wideband-gap insulators, LaAlO<sub>3</sub> (~5.6 eV) and SrTiO<sub>3</sub> (~3.2 eV).<sup>1</sup> This q-2DEG behavior, different from the strained semiconductor heterointerface, is attributed to the electronic reconstruction of Ti<sup>4+</sup> into Ti<sup>3+</sup> ions at the interface to minimize the electrostatic potential due to polar discontinuity between (LaO)<sup>+</sup> and (TiO<sub>2</sub>)<sup>0</sup> layers; this is known as the polar catastrophe model. The discovery boosted an extensive research in polar perovskite ABO<sub>3</sub>/SrTiO<sub>3</sub> heterointerfaces with different 3d cations at the B-site. Interestingly, the heterointerface with LaTiO<sub>3</sub><sup>8,9</sup> and LaVO<sub>3</sub><sup>10</sup> shows metallicity, however, it remains insulating for LaMnO<sub>3</sub><sup>11</sup> and LaCrO<sub>3</sub>.<sup>12</sup> It is observed that the d-cation charge reorganization for (Mn, Cr) cations lowers the electrostatic potential and hinders the q-2DEG state. Moreover, the insulating state in LaTiO<sub>3</sub> and LaVO<sub>3</sub> is of Mott-type (due to highly correlated 3d electrons), which allows a weak insulating gap and minimal carrier mobility than the 3p Al-based prototype LaAlO<sub>3</sub> system. It is shown that strain-mediated lattice distortion can suppress the weak Mott gap in LaTiO<sub>3</sub> (~0.1 eV), showing an extrinsic 3D bulk transport; although for LaVO<sub>3</sub> (~1.1 eV), the conduction is of 2D-type.

Importantly, the conducting interface is not limited to polar oxides, but also reported for non-polar perovskites, e.g., lattice strain driven for CaZrO<sub>3</sub>,<sup>13</sup> while extrinsic oxygen vacancy driven for CaHfO<sub>3</sub>.<sup>14</sup> Thus, minimal structural imperfection may also lead to 3D bulk conductivity, either in the SrTiO<sub>3</sub> substrate by cation intermixing (doping) due to high energy plume kinematics or in the thin film from oxygen non-stoichiometry.

On the ground, the interface conductivity can be driven by both “intrinsic” polar discontinuity,<sup>15</sup> or strain-induced weak polarization<sup>7</sup> (2D transport) and “extrinsic” cation inter-diffusion<sup>16</sup> or oxygen vacancies<sup>17–19</sup> (3D transport). This puts the idealness of real samples as the primary condition for intrinsic 2D transport, followed by a wideband gap of two constituent oxides with a low lattice mismatch. Owing to this, 4p Ga-based band insulators, LaGaO<sub>3</sub> (~4.4 eV)<sup>20</sup> and NdGaO<sub>3</sub> (~3.8 eV)<sup>21</sup> show q-2DEG transport similar to the 3p Al-based prototype LaAlO<sub>3</sub> system, however, the low-stability of Gallium makes the growth complex for exploring a clear mechanism. In this work, we explore the 3d Sc-based wideband gap insulator LaScO<sub>3</sub> (~5.7 eV), and report, theoretically and experimentally, a “polar discontinuity”-driven q-2DEG system in the LaScO<sub>3</sub>/SrTiO<sub>3</sub> heterostructure, quite analogous to the prototype 3p-based LaAlO<sub>3</sub>/SrTiO<sub>3</sub> system.

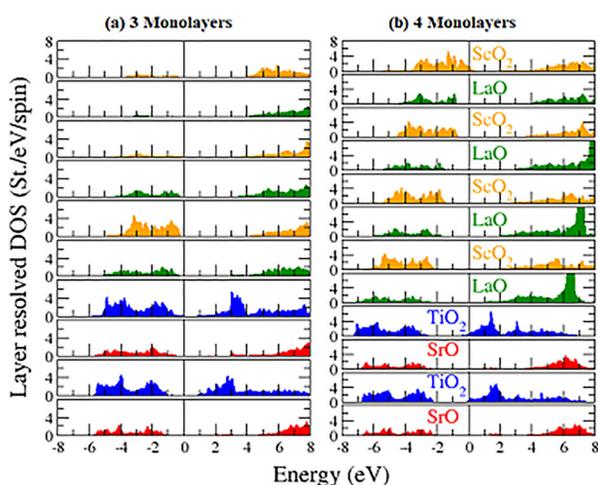
The structural and electronic properties of bulk  $\text{LaScO}_3$  and  $\text{SrTiO}_3$ , and those of  $\text{LaScO}_3/\text{SrTiO}_3$  heterostructures are studied by means of the full potential linearized augmented plane wave<sup>22</sup> (FP-LAPW) method as implemented in the WIEN2K suite of programs. The details of the calculations are provided in the [supplementary material](#).

For the bulk  $\text{SrTiO}_3$  and  $\text{LaScO}_3$ , the pseudo-cubic equilibrium lattice constant is determined as 3.94 Å and 4.07 Å, respectively, which are in good agreement with the experimental data, within 1% of error. From these parameters, it can be anticipated that the epitaxially grown  $\text{LaScO}_3$  films would be compressively strained on the  $\text{SrTiO}_3$  substrate with a lattice mismatch of 3.2%. Within similar approximations, the computed lattice constant of 3.82 Å for  $\text{LaAlO}_3$  shows a tensile nature of the strain at the  $\text{LaAlO}_3/\text{SrTiO}_3$  hetero-interface. Thus, these findings suggest that although  $\text{LaScO}_3$  and  $\text{LaAlO}_3$  are isoelectronic and isostructural systems, the  $\text{LaScO}_3/\text{SrTiO}_3$  represents a compressively strained system, in contrast to the  $\text{LaAlO}_3/\text{SrTiO}_3$ , which is tensile strained.

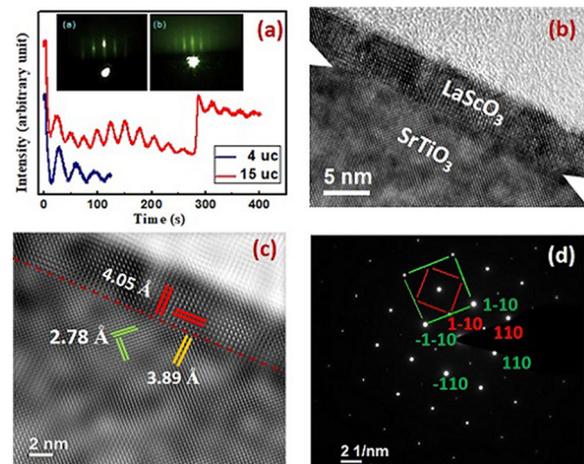
Besides, the electronic bandgaps ( $E_g$ ) of  $\text{SrTiO}_3$ ,  $\text{LaScO}_3$ , and  $\text{LaAlO}_3$  are computed to be 2.0 eV, 2.8 eV, and 3.6 eV, respectively. Thus, we find that  $E_g(\text{SrTiO}_3) < E_g(\text{LaScO}_3) < E_g(\text{LaAlO}_3)$ . Note that, although the  $E_g$  values are considerably smaller than the experimental values, these values still serve as a good approximation in empirically suggesting that electrons will flow into the  $\text{SrTiO}_3$  substrate from the  $\text{LaScO}_3$  and  $\text{LaAlO}_3$ . The electronic structure of the structurally relaxed  $\text{LaScO}_3/\text{SrTiO}_3$  heterostructure is described in terms of their layer resolved density of states (DOS) and band structure, as shown for two cases with 3 and 4  $\text{LaScO}_3$  MLs in [Figs. 1\(a\)](#) and [1\(b\)](#), respectively. For 3 ML  $\text{LaScO}_3/\text{SrTiO}_3$ , the  $\text{LaO}/\text{TiO}_2$  interface is insulating with a bandgap of 0.6 eV. The valence band spectra are dominated by the O 2p states of the substrate, while the conduction band minimum (CBM) is dominated by the Ti 3d states. The Sc 3d states are ~1 eV above the CBM. On the other hand, DOS spectra for 4 ML  $\text{LaScO}_3/\text{SrTiO}_3$  show finite states at the Fermi energy, revealing a q-2DEG state. Importantly, the critical thickness of 4 MLs for the emergence of q-2DEG in  $\text{LaScO}_3/\text{SrTiO}_3$  is identical to that for the

$\text{LaAlO}_3/\text{SrTiO}_3$ .<sup>4</sup> Furthermore, the layer resolved DOS reveals that the conducting carriers are derived from the Ti 3d bands with confinement to nearly 2 MLs of  $\text{SrTiO}_3$ . The total DOS at Fermi energy is determined to be 3.3 states/eV/spin, of which the interface  $\text{TiO}_2$  layer contributes ~15% and the sub-interface  $\text{TiO}_2$  layer has its contribution as ~11%. The systematic downward shift in the Ti 3d band of the  $\text{SrTiO}_3$  substrate, due to the increasing built-up of the electrostatic potential in the  $\text{LaScO}_3$  films, is however compensated by the upward shift of the O 2p bands of  $\text{LaScO}_3$ . As evident from [Fig. 1\(b\)](#), the O 2p bands of the surface  $\text{ScO}_2$  layers therefore are introduced with holes. The very kind of charge transfer, from surface layers to the  $\text{TiO}_2$  hetero-interface layers, is previously observed in the  $\text{LaAlO}_3/\text{SrTiO}_3$  heterostructure, in line with the predictions of the polar catastrophe model.

To test the theoretical finding of q-2DEG in the  $\text{LaScO}_3/\text{SrTiO}_3$  heterostructure, the epitaxial thin films of  $\text{LaScO}_3$  with varying thickness (3–15 unit cell) are deposited on the (001)  $\text{TiO}_2$ -terminated  $\text{SrTiO}_3$  single-crystal substrate by the pulsed laser deposition (PLD) technique with layer-by-layer growth monitoring by *in situ* reflection high-energy electron diffraction (RHEED). The details of the growth and characterization tools are provided in the supplementary section. [Figure 2\(a\)](#) shows the regular RHEED intensity oscillations for 4- and 15-unit cell (uc) thick films recorded *in situ* during the growth, which clearly exhibits the two-dimensional (2D) epitaxial growth of the  $\text{LaScO}_3$ . The 2D streaky RHEED pattern shown in the inset of [Fig. 2\(a\)](#) confirms the layer-by-layer growth for the  $\text{LaScO}_3$  film with identical distance between two streaks to that for the  $\text{SrTiO}_3$  substrate. Complementing the RHEED results, the high-resolution x-ray diffraction (HRXRD) pattern for the thicker (~40 nm) film shows only the (00l) reflections of the perovskite structure with the out-of-plane lattice parameter,  $c = 4.058$  Å (see [Fig. S1](#) in the [supplementary material](#)). Moreover, the surface analysis by atomic force microscopy for the 8 uc thick film reveals the persistence of similar terraces (see [Fig. S2](#) in the [supplementary material](#)), as for the before-growth  $\text{TiO}_2$ -terminated surface of the  $\text{SrTiO}_3$  substrate with approximately 0.39 nm step



**FIG. 1.** The layer resolved density of states (DOS) for the  $\text{LaScO}_3/\text{SrTiO}_3$  heterostructure with (a) 3 monolayers and (b) 4 monolayers of the  $\text{LaScO}_3$  film.



**FIG. 2.** (a) RHEED intensity oscillation during the growth of the thin film along with the RHEED pattern of the bare substrate (left) and thin film (right). (b) XTEM image of the 10 uc structure. (c) Fourier filtered XTEM image and (d) SAED pattern of the same structure and same image shown in (b).

height. This indicates that  $\text{LaScO}_3$  adopts a pseudo-cubic symmetry over the  $\text{SrTiO}_3$  substrate, giving an abrupt interface between two oxides. The interface quality is further examined for the 10 uc thick film with cross-sectional transmission electron microscopy (XTEM) along with the selected area electron diffraction (SAED) patterns. The XTEM on the 5 nm scale shows the clear boundary between the  $\text{SrTiO}_3$  substrate and the  $\text{LaScO}_3$  thin film with a thickness of 4.56 nm, as shown in Fig. 2(b). The Fourier filtered XTEM image for the same micrograph shows an atomically flat and coherent heterointerface with smooth relaxation in the thin film [see Fig. 2(c)], excluding any cation inter-diffusion between the substrate and thin film. The lattice parameter analysis by XTEM and SAED [see Fig. 2(d)] gives the single-domain and tetragonally strained  $\text{LaScO}_3$  thin film with in-plane  $a^* = 4.05 \text{ \AA}$ , which is in well consistent with  $a^* = 4.058 \text{ \AA}$  from the HRXRD study.

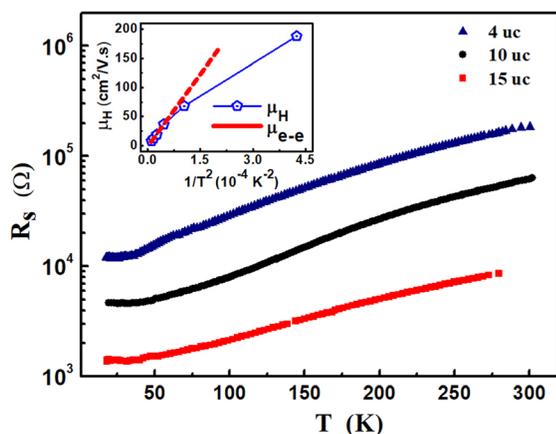
The highly crystalline  $\text{LaScO}_3/\text{SrTiO}_3$  interface is further subjected to sheet resistance measurement as a function of temperature,  $R(T)$  from room temperature to 30 K. The heterointerface with  $\text{LaScO}_3$  thickness  $\geq 4$  uc shows metallic behavior down to 30 K [see Fig. 3], which indicates the q-2DEG formation at the  $\text{LaScO}_3/\text{SrTiO}_3$  heterointerface. The measured room temperature carrier concentration ( $n_s$ ) of the order of  $10^{13} \text{ cm}^{-2}$  at the interface and the carrier mobility ( $\mu_H$ ) of  $4\text{--}7 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$  (for 4–15 uc) from Hall measurement are almost similar to the prototype  $\text{LaAlO}_3/\text{SrTiO}_3$ .<sup>1,23</sup> Thus, considering the nearly equal bandgap and dielectric constant of  $\text{LaScO}_3$  ( $\sim 5.7 \text{ eV}$ , 29) to  $\text{LaAlO}_3$  ( $\sim 5.6 \text{ eV}$ , 25), at the first point, the observed interface conductivity in our heterointerface above critical thickness (i.e.,  $\geq 4$  uc) can be attributed to the polar discontinuity between polar  $(\text{LaO})^+$  and non-polar  $(\text{TiO}_2)^0$  layers, similar to  $\text{LaAlO}_3/\text{SrTiO}_3$ .<sup>1,15</sup>

Now, we discuss the possible origin mechanism of a conducting interface in transport measurements, considering both “intrinsic” polar discontinuity (2D transport) and “extrinsic” cation disorder and oxygen vacancies (3D transport). The foremost important thing is that our epitaxial thin film is grown with a laser fluence of  $\sim 1 \text{ J/cm}^2$ , similar to  $\text{LaAlO}_3$ ,<sup>24</sup> while it is significantly lower than for  $\text{LaTiO}_3$ ,<sup>8,9</sup>  $\text{LaVO}_3$ ,<sup>10</sup>  $\text{LaGaO}_3$ ,<sup>20</sup> etc. to exclude the possibility of high energy La/Sr

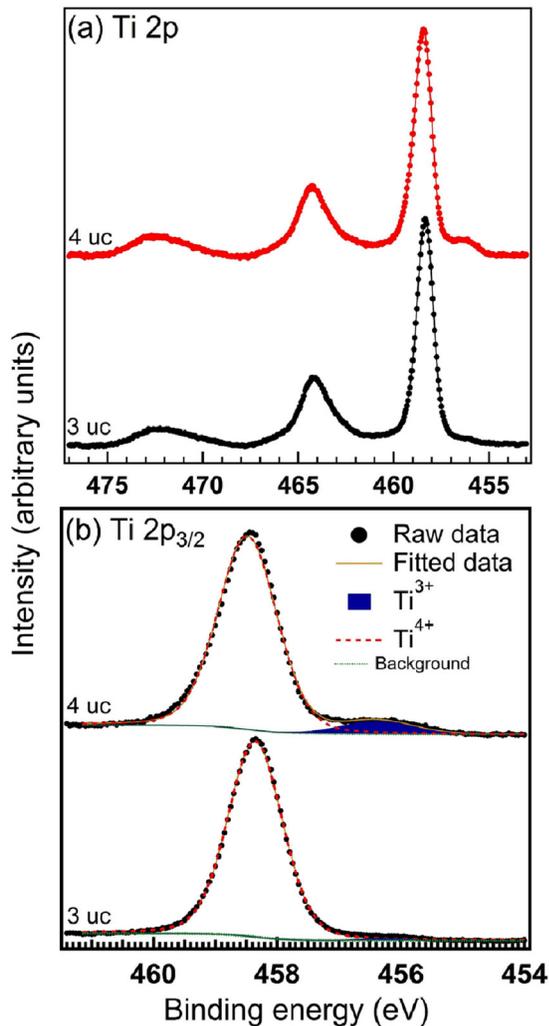
inter-diffusion (doping) to the  $\text{SrTiO}_3$  substrate, which is further supported by the XTEM study. To exclude oxygen vacancies in the  $\text{TiO}_2$ -terminated  $\text{SrTiO}_3$  substrate, the high insulating nature after annealing of the bare substrate at deposition conditions is verified before the growth. Furthermore, the  $\text{LaScO}_3$  thin film deposition is performed in  $p_{\text{O}_2} \sim 10^{-4}$  mbar, similar to  $\text{LaAlO}_3$ ,<sup>25–27</sup> which excludes any major contribution to interface conductivity from the oxygen vacancies. Moreover, on lowering of temperature from 300 K to 50 K, a minimal decrease in  $n_s \sim 9.4\text{--}4.7 \times 10^{13} \text{ cm}^{-2}$  suggests a 2D transport behavior (see Fig. S3 in the supplementary material). More importantly, the carrier mobility shows  $1/T^2$  dependence at high temperatures (150 K–300 K) in accordance with electron–electron interactions at the 2D interface, a rather exponential increase for electron–phonon interactions in 3D transport.<sup>25</sup> At lower temperatures, the mobility shows a saturation-like behavior to the low-temperature limit with the highest carrier mobility of  $1.88 \times 10^2 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$  at 50 K. Thus, the transport measurements reveal the formation of q-2DEG state at the  $\text{LaScO}_3/\text{SrTiO}_3$  heterointerface, primarily driven by “intrinsic” polar discontinuity in the system.

Here, we point out that the obtained  $n_s \sim 9.4\text{--}4.7 \times 10^{13} \text{ cm}^{-2}$  (for 10–15 uc) is significantly lower than the calculated charge transfers due to polar-discontinuity i.e.,  $0.5e^-/\text{Ti}$  or  $n_s \simeq 3 \times 10^{14} \text{ cm}^{-2}$  in the polar catastrophe model. The lower experimental  $n_s$  value can be directly associated with the presence of two kind of electrons, free (or mobile) as considered in the polar catastrophe scenario and second localized electrons either “intrinsically” in  $3d$ -based oxides or “extrinsically” trapped in defect states.<sup>28</sup> The presence of localized electrons reduces the effective charge transfer due to polar discontinuity. The picture of two kind “free” and “localized” charge carriers is well supported by Shubnikov-de Haas oscillations measurement.<sup>29</sup> Besides, as an alternative, Yu *et al.*<sup>30</sup> proposed that polar discontinuity is thermodynamically destabilized by the spontaneous formation of defects like oxygen vacancies leading to a conducting interface, while some of the oxygen vacancies are further compensated by anti-site pairs (cation disorder), thus, reducing the carrier density in comparison to that calculated from polar discontinuity.

The experimental existence of electrons which contribute to the conducting interface is analyzed by x-ray photoelectron spectroscopy (XPS). In Fig. 4, we compare the Ti  $2p$  core level spectra of 3 uc and 4 uc thick  $\text{LaScO}_3$  films grown on  $\text{TiO}_2$ -terminated  $\text{SrTiO}_3$ . For non-conducting  $\text{LaScO}_3$  (3 uc)/ $\text{SrTiO}_3$ , spin-orbit doublet peaks of Ti  $2p_{3/2}$  and Ti  $2p_{1/2}$  appear at 458.4 and 464.2 eV core level binding energy (BE), respectively, corresponding to the  $4^+$  charge state of Ti ions. In comparison, for the conducting  $\text{LaScO}_3$  (4 uc)/ $\text{SrTiO}_3$ , peaks corresponding to  $\text{Ti}^{4+}$  appear at 0.1 eV higher BE compared to 3 uc  $\text{LaScO}_3/\text{SrTiO}_3$ . Besides, we can clearly observe the emergence of an extra well resolved feature at the lower BE side of the Ti  $2p_{3/2}$  main peak of 4 uc  $\text{LaScO}_3/\text{SrTiO}_3$ . To quantify the peak parameters, energy position and the full width at half maximum (FWHM), we have performed  $\chi^2$  iterative fitting of the Ti  $2p_{3/2}$  region using two components corresponding to the main peak and weaker intensity lower BE side feature. These fittings are shown in Fig. 4(b). The energy position of the lower BE feature [shaded region in Fig. 4(b)] is found to be separated by 1.9 eV from the main peak and such a feature has been attributed to the  $\text{Ti}^{3+}$  valence state.<sup>3,31–38</sup> This  $\text{Ti}^{3+}$  related feature, a consequence of the polar catastrophe induced electronic reconstruction of Ti ions at the interface, has been taken as the signature of quasi



**FIG. 3.** The thermal variation of sheet resistance showing a metallic behavior. The inset shows the hall mobility of the 15 uc  $\text{LaScO}_3/\text{SrTiO}_3$  structure plotted against  $1/T^2$  with a high temperature linear variation (red line), corresponding to e-e (2D) interactions.



**FIG. 4.** (a) Ti 2p core-level photoemission spectra of the 3 uc and 4 uc LaScO<sub>3</sub>/SrTiO<sub>3</sub>. Spectra have been normalized at the highest peak and staggered vertically for clarity. (b) Ti 2p<sub>3/2</sub> core-level photoemission spectra for 3 uc and 4 uc LaScO<sub>3</sub>/SrTiO<sub>3</sub>. Experimental spectra (open circles), fitted spectra (green solid line), deconvoluted components used to fit Ti<sup>4+</sup> (red dashed line), and Ti<sup>3+</sup> (blue shaded) along with the simulated Shirley background (pink dashed line) are also shown.

two-dimensional electron gas (q-2DEG) in polar/non-polar oxide heterostructures. The relative percentage (normalized peak area) of Ti<sup>3+</sup> to Ti<sup>4+</sup> has been estimated to be 6.8% for 4 uc LaScO<sub>3</sub>/SrTiO<sub>3</sub>, while it is negligible (0.85%) for 3 uc LaScO<sub>3</sub>/SrTiO<sub>3</sub>. Peak fittings revealed that the FWHM of the Ti 2p<sub>3/2</sub> (Ti<sup>4+</sup>) for 3 and 4 uc LaScO<sub>3</sub>/SrTiO<sub>3</sub> turns out to be 1.05 and 1.15 eV, respectively. The shift of the Ti 2p core level toward the higher BE side for the conducting interface (4 uc) and the increase in its FWHM compared to non-conducting 3 uc LaScO<sub>3</sub>/SrTiO<sub>3</sub> can be the consequence of the band bending effect and it has also been considered as the evidence for the presence of q-2DEG in polar/non-polar systems.<sup>32,33,37</sup>

In summary, the highly crystalline LaScO<sub>3</sub> epitaxial thin films are grown on a (001) TiO<sub>2</sub>-terminated SrTiO<sub>3</sub> substrate by the PLD

technique with two-dimensional growth ensured by *in situ* RHEED. The abrupt interface quality with no substrate-film inter-diffusion is confirmed with the cross-sectional TEM study. The electric transport measurements reveal the formation of q-2DEG at the heterointerface for films with LaScO<sub>3</sub> thickness  $\geq 4$  uc, at room temperature carrier concentration of  $10^{13}$  cm<sup>-2</sup> at the interface, and a mobility of 4–7 cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup>, quite similar to the prototype LaAlO<sub>3</sub>/SrTiO<sub>3</sub> q-2DEG system. Finally, the XPS study reveals electronic reconstruction of Ti ions at the interface as a signature of the “Polar Catastrophe” origin of the q-2DEG state. On top of this, the DFT calculations show the emergence of q-2DEG in the LaAlO<sub>3</sub>/SrTiO<sub>3</sub> heterostructure in accordance with the polar catastrophe model, in which the increasing electrostatic potential due to the increasing LaScO<sub>3</sub> film thickness transfers charge from the surface layer to the hetero-interface. Thus, the study provides a 3d band-insulator based q-2DEG system, beyond the existing 3p-based LaAlO<sub>3</sub>/SrTiO<sub>3</sub>, to explore futuristic quantum applications.

See the [supplementary material](#) which contains the theoretical calculations and experimental methods of the present study. Figs. S1–S3 illustrate the HRXRD, AFM, and Hall mobility measurement of the LaScO<sub>3</sub>/SrTiO<sub>3</sub> heterostructure, respectively.

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